**Measurement of:** I-V Measurement

**Equipment:** I-V Measurement (Keithley 4200SCS)

**Property Measured:**

Electrical Characterization is usually performed on the Two basic device types

- Transistors - BJT, MOS, IGBT etc.
- Diodes - PN, Schottky, Gated etc.

**Photograph (small size)**

![Photograph](image)

**Basic Principle:** Model 4200 Semi Conductor Characterization System (SCS) is used to measure DC I-V of two terminal and three terminal semiconductor devices. The system supports up to Two Source-Measure Units. Electrical Characterization is usually performed on the Two basic device types

- Transistors - BJT, MOS, IGBT etc.
- Diodes - PN, Schottky, Gated etc.

**Capabilities:** The instrument can do the I-V measurement of thin film/bulk sample

**Sample Requirement:** thin film/bulk sample